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Large reduction of thermal conductivity leading to enhanced thermoelectric performance in p-type Mg3Bi2-YbMg2Bi² solid solutions

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Intensifying the phonon scattering *via* point defect engineering has been demonstrated to be particularly effective in minimizing the lattice thermal conductivity for enhancing thermoelectric performance. In this work, significant phonon scattering has been realized by alloying YbMg2Bi2 with Mg3Bi2. The substantial mass difference between the host atom Yb and the alloying atom Mg leads to an intense phonon scattering effect that significantly reduces the lattice thermal conductivity. The room-temperature lattice thermal conductivity decreases from ∼2.7 W m⁻¹ K⁻¹ for YbMg2Bi_{1.96} to ∼0.8 W m⁻¹ K⁻¹ for Yb_{0.7}Mg_{0.3}Mg₂Bi_{1.96}, a reduction of ∼70%. Benefiting from the greatly reduced thermal conductivity, the average *ZT* has been effectively improved from ∼0.46 for YbMg₂Bi_{1.96} to ∼0.61 for Yb_{0.8}Mg_{0.2}Mg₂Bi_{1.96}, an enhancement of ∼33%. In addition, the predicted maximum heat-to-electricity conversion efficiency can be increased from ~7% for YbMg2Bi1.96 to ∼10% for Yb0.8Mg0.2Mg2Bi1.96.

Introduction

Thermoelectric materials have attracted extensive interest in the last several decades due to their capability of converting waste heat into electricity. As the main challenge preventing the widespread use of thermoelectrics is their low conversion efficiency, improving the heat-to-electricity conversion efficiency is particularly critical.^{[1-4](#page-6-0)} The thermoelectric energy conversion efficiency of a material is determined by the Carnot efficiency and the material's dimensionless thermoelectric figure of merit (*ZT*), defined as $ZT = S^2 \sigma T / \kappa$, where *S*, *σ*, *κ*, and *T* are the Seebeck coefficient, electrical conductivity, thermal conductivity, and absolute temperature, respectively. Total thermal conductivity contains the lattice, electronic, and bipolar contributions: $K_{total} = K_l + K_e + K_B$. Therefore, a good thermoelectric material with a high *ZT* should have a high Seebeck coefficient, high electrical conductivity and low thermal conductivity.

Thus far, high *ZT*s have been reported in several classes of bulk thermoelectric materials, such as half-Heuslers^{[5-7](#page-6-1)}, lead telluride^{[8,](#page-6-2) [9](#page-7-0)}, bismuth telluride^{[10,](#page-7-1) [11](#page-7-2)}, and Zintls^{[12-14](#page-7-3)}. Among these thermoelectric materials, Zintl phase compounds are highly promising due to their complex crystal structures along with their large numbers of

atoms per unit cell. [15,](#page-7-4) [16](#page-7-5) Zintl compounds contain the covalently bonded networks of complex anions or metalloids ("electroncrystal" electronic structure) and cations ("phonon-glass" characteristic). [13,](#page-7-6) [14](#page-7-7) A variety of high-performance Zintl phases, such as Yb₁₄MnSb₁₁¹⁷⁻²⁰, Mg_{3+x}Sb_{1.5}Bi_{0.5}²¹⁻²⁷, AZn₂Sb₂ (A = Sr, Ca, Yb, or Eu)^{[15,](#page-7-4) [28-33](#page-7-10)}, BaGa₂Sb₂,^{[34,](#page-7-11) [35](#page-7-12)} and A₅M₂Sb₆ (A = Ca, or Yb; M = Al, Ga, or In)[36-40](#page-7-13), have been studied for potential thermoelectric applications. In addition to the Sb-based Zintl compounds, thermoelectric properties of the analogous Bi-based compounds have also been investigated.^{[41-47](#page-7-14)} Enhanced thermoelectric performance of Bi-based materials has been realized by alloying YbMg₂Bi₂ with EuMg₂Bi₂ and CaMg₂Bi₂. Substitution of isoelectronic ions introduces disorder to scatter phonons without significantly disrupting the electrical conductivity. [14](#page-7-7) This is a highly effective method to improve the thermoelectric performance of many other materials as well. [48-53](#page-7-15) It has been reported that YbMg₂Bi₂ has good thermoelectric performance but with relatively high lattice thermal conductivity. Therefore, it is possible to further improve the thermoelectric performance of YbMg₂Bi₂ by reducing the lattice thermal conductivity via phonon engineering, e.g., alloying YbMg₂Bi₂ with Mg₃Bi₂ (for a larger mass difference in the cationic site). In addition, it should be noted that the pure phase of any AB_2M_2 (A = Ca, Ba, Sr, Yb, or Eu; B = Mn, Zn, or Cd; M = Sb or Bi) Zintl compound, which is crucial for the high thermoelectric performance, is not easily obtainable since the A or B in AB_2M_2 vaporizes or reacts with the reaction container.^{[31,](#page-7-16) [44](#page-7-17)} Therefore, optimizing the composition to obtain a high quality specimen can effectively improve the thermoelectric performance.

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Fig. 1 (a) XRD patterns of YbMg₂Bi₂, YbMg₂Bi_{1.98}, and Yb_{1-x}Mg_xMg₂Bi_{1.96} (*x* = 0, 0.1, 0.2, and 0.3) and (b) zoomed-in XRD patterns of Yb_{1-x}Mg_xMg₂Bi_{1.96} (*x* = 0, 0.1, 0.2, and 0.3) between 22° and 28°; (c) temperature-dependent heat capacity of YbMg2Bi2, YbMg2Bi1.98, and Yb1-xMgxMg2Bi1.96 (*x* = 0, 0.1, 0.2, and 0.3); and (d) dependence of lattice parameters on composition for Yb1-*x*Mg*x*Mg2Bi1.96.

Therefore, the motivation for this work is first to achieve the pure-phase specimen of YbMg2Bi² by optimization of the composition. Afterwards, in order to further improve the thermoelectric properties of the YbMg₂Bi₂-based materials, solid solutions between the pure-phase YbMg₂Bi₂ and Mg₃Bi₂ are prepared. Our results show that the room-temperature lattice thermal conductivity of YbMg2Bi_{1.96} is ~2.7 W m⁻¹ K⁻¹, but it is only \sim 0.8 W m⁻¹ K⁻¹ for Yb_{0.7}Mg_{0.3}Mg₂Bi_{1.96}, a reduction of \sim 70%. Benefiting from the greatly reduced thermal conductivity, the average *ZT* is effectively improved from ~0.46 for YbMg₂Bi_{1.96} to ∼0.61 for Yb_{0.8}Mg_{0.2}Mg₂Bi_{1.96}, an enhancement of ~33%.

Experimental

Synthesis

Ytterbium pieces (Yb, Sigma Aldrich, 99.9%, chunks), magnesium turnings (Mg, Sigma Aldrich, 99.9%, pieces), and bismuth ingots (Bi, Sigma Aldrich, 99.999%, chunks) were weighed according to the stoichiometry of YbMg2Bi2, YbMg2Bi1.98, and Yb1-*x*Mg*x*Mg2Bi1.96 (*x* = 0, 0.1, 0.2, and 0.3) and loaded into a stainless-steel jar in a glovebox under argon atmosphere. The materials were ball-milled for 4 h by using a high energy ball mill (SPEX 8000D). The powders were then loaded into a graphite die with an inner diameter of 12.7 mm in a glovebox, and immediately sintered by alternatingcurrent hot pressing at 933 K under pressure of ∼80 MPa for 2 min. The hot-pressed disks are about 2-3 mm thick.

Characterization

A PANalytical multipurpose diffractometer with an X'celerator detector (PANalytical X'Pert Pro) was used to characterize the

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Fig. 2 (a) Temperature-dependent electrical conductivity, (b) composition-dependent Hall carrier concentration, and (c) temperature-dependent Seebeck coefficient of Yb1-*x*Mg*x*Mg2Bi1.96 (*x* = 0, 0.1, 0.2, and 0.3); (d) Hall-carrier-concentration-dependent Seebeck coefficient of Yb1-*x*Mg*x*Mg2Bi1.96 and previously studied compositions, including Eu0.5Yb0.5Mg2Bi2, Eu0.25Yb0.25Ca0.5Mg2Bi2, and Eu0.2Yb0.2Ca0.6Mg2Bi2. [43](#page-7-18) The inset in (c) is the composition-dependent band gap of Yb1-*x*Mg*x*Mg2Bi1.96 (*x* = 0.2 and 0.3 from the Goldsmid-Sharp formula and *x* = 0 and 0.1 extrapolated). The solid line in (d) is the calculated Pisarenko plot with *m** = 0.64 *m*⁰ at room temperature. [12](#page-7-3)[, 54,](#page-7-19) [55](#page-7-20)

phase composition of the prepared samples. The morphology and elemental mapping of a representative sample were characterized by a scanning electron microscope (SEM) (LEO 1525) and energydispersive X-ray spectroscopy (JEOL 6340F), respectively. The electrical resistivity (ρ , ρ =1 $/\sigma$) and Seebeck coefficient of the bar-shaped samples were simultaneously measured in a commercial system (ZEM-3, ULVAC) using the four-point direct current switching method. The total thermal conductivity was calculated using $\kappa_{\text{total}} = DC_{\rho}d$, where *D* (Fig. S1), C_{p} , and *d* (Table S1) are thermal diffusivity, specific heat capacity, and volume density, respectively. The thermal diffusivity (*D*) was measured using a laser flash apparatus (LFA 457, NETZSCH). The specific heat (*Cp*) was measured using a differential scanning calorimetry thermal analyzer (404 C, NETZSCH). The volumetric density (*d*) was

determined by the Archimedean method. The room temperature Hall coefficient R_H was measured using a Physical Properties Measurement System (PPMS Dynacool, Quantum Design) with a magnetic field of 3 T and an electrical current of 8 mA. The Hall carrier concentration n_H was calculated by $n_H = 1/(eR_H)$.

Results and discussion

Fig. 1(a) shows the X-ray diffraction (XRD) patterns of the prepared YbMg₂Bi₂, YbMg₂Bi_{1.98}, and Yb_{1-x}Mg_xMg₂Bi_{1.96} ($x = 0$, 0.1, 0.2, and 0.3). Except for the Bi-impurity phase (marked by a black arrow) in YbMg₂Bi₂ and YbMg₂Bi_{1.98}, all of the diffraction peaks can be indexed to the structure of CaAl₂Si₂ (space group $\overline{P3}m1$). The

Fig. 3 Temperature-dependent (a) total thermal conductivity, (b) sum of lattice and bipolar thermal conductivity, (c) lattice thermal conductivity, and (d) bipolar thermal conductivity of Yb1-*x*Mg*x*Mg2Bi1.96 (*x* = 0, 0.1, 0.2, and 0.3).

presence of the Bi-impurity phase should be due to the vaporization of Mg at elevated temperature. Additionally, the peaks shift to higher angles with increasing Mg content (Fig. 1(b)). To eliminate the Bi-impurity phase, we reduced the Bi content in the composition of YbMg₂Bi₂ to YbMg₂Bi_{1.96}. In this case, all of the diffraction peaks can be well indexed to the CaAl₂Si₂ crystal structure without the presence of secondary phases. We have also conducted the specific heat measurement, and the peak around 544 K (*i.e.*, the melting point of Bi) can be observed in both YbMg₂Bi₂ and YbMg₂Bi_{1.98}, but it disappears in all of the Yb₁. *^x*Mg*x*Mg2Bi1.96 samples (Fig. 1(c)).[43](#page-7-18) The lattice parameters of the Yb1-*x*Mg*x*Mg2Bi1.96 solid solutions decrease monotonically with increasing Mg concentration (Fig. 1(d)), in good agreement with the Vegard's law. Such a reduction in the lattice parameters should be attributed to the smaller ionic radius of Mg^{2+} (65 pm) than that of Yb^{2+} (93 pm). The microstructure of a typical $Yb_{0.8}Mg_{0.2}Mg_2Bi_{1.96}$ sample (Fig. S2) shows homogeneous distribution of each element with no observable micro-holes, which indicates its high relative density. Therefore, it is clear that Mg successfully substitutes for Yb to form the Yb1-*x*Mg*x*Mg2Bi1.96 solid solutions.

Fig. 2(a) shows the temperature-dependent electrical conductivity of Yb_{1-x}Mg_xMg₂Bi_{1.96} samples. The electrical conductivity of Yb_{1-x}Mg_xMg₂Bi_{1.96} decreases with the increasing temperature, showing the typical behavior of degenerated semiconductors. In addition, an increase in electrical conductivity can also be observed with increasing Mg content from *x* = 0 to *x* = 0.3, which should be ascribed to the increased Hall carrier concentration n_H (Fig. 2(b)). On one hand, this can be explained by the concentration of *A*-site defects in AB₂M₂ compounds^{[28](#page-7-10)}, i.e. the Mg- and Yb-site defects in Mg₃Bi₂ and YbMg₂Bi₂, respectively. In fact, Mg is more electronegative than Yb. With increasing cation electronegativity, the defect formation enthalpy for cation vacancies decreases, which results in a smaller energy barrier for cation vacancy formation and an increasing amount of hole carrier concentration in the Mg₃Bi₂-YbMg₂Bi₂ solid solutions. On the other hand, the replacement of the isoelectronic cations with those of different electronegativity will lead to the variation in carrier **Journal Name ARTICLE**

Fig. 4 (a) Temperature-dependent *ZT* values of Yb1-*x*Mg*x*Mg2Bi1.96 (*x* = 0, 0.1, 0.2, and 0.3) in comparison with those of YbMg2Bi² [42](#page-7-21) and Yb0.5Ca0.5Mg2Bi2; [44](#page-7-17) (b) comparison of the average figure of merit among Yb1-*x*Mg*x*Mg2Bi1.96 (*x* = 0, 0.1, 0.2, and 0.3) and results from May *et al.* and Shuai *et al.*; (c) calculated engineering figure of merit and (d) leg efficiency of Yb_{1-x}Mg_xMg₂Bi_{1.96} ($x = 0$, 0.1, 0.2, and 0.3).

concentration.[56-59](#page-7-22) Therefore, increasing the Mg concentration will increase the Hall carrier concentration in the p-type Yb_1 . *^x*Mg*x*Mg2Bi1.96 semiconductor.

Fig. 2(c) shows the temperature-dependent Seebeck coefficient of Yb1-*x*Mg*x*Mg2Bi1.96 samples. Due to the variation in the Hall carrier concentration, the room-temperature Seebeck coefficient gradually decreases with the increasing Mg concentration. Fig. 2(d) shows the Pisarenko plot (Hall-carrier-concentration-dependent Seebeck coefficient) with $m^* = 0.64$ m_0 at room temperature (see supplementary information for details). Similar to that of Eu0.5Yb0.5Mg2Bi2, Eu0.25Yb0.25Ca0.5Mg2Bi2, and Eu0.2Yb0.2Ca0.6Mg2Bi² solid solutions, all of the current experimental data fall nearly completely on the fitting line, indicating that the valence band structure remains almost unchanged. In addition, it should be noted that the Seebeck coefficient of the samples with higher Mg concentration demonstrates a noticeable bipolar effect. This should be ascribed to the narrowing of the band gap, since Mg₃Bi₂ was reported to be a semi-metal (*i.e.*, with zero band gap). The band gap *E*^g can be analyzed by the Goldsmid–Sharp formula $E_g = 2e|S|_{\text{max}} T_{\text{max}}$, where *e*, S_{max} , and T_{max} are the electron charge, the maximum Seebeck coefficient, and the corresponding temperature, respectively.[60,](#page-7-23) [61](#page-7-24) As shown in the inset of Fig. 2(c), *E*^g of the samples linearly decreases with increasing Mg content (the band gap among *x* = 0 and *x* = 0.1 is extrapolated from *x* = 0.2 and $x = 0.3$). As a consequence of the decreased E_g , it is obvious that

the temperature corresponding to the maximum Seebeck coefficient for the samples shifts gradually from high to low temperature as the Mg content increases.

Fig. 3(a) shows the temperature-dependent *κ*_{total} of Yb₁. *^x*Mg*x*Mg2Bi1.96 samples, where a substantial decrease in *κ*total with increased Mg concentration can be observed. To clearly reveal the phonon scattering effect, the sum of lattice thermal conductivity K_{L} and bipolar thermal conductivity K_{B} is obtained by subtracting the electronic thermal conductivity κ_e ($\kappa_e = L \sigma T$, where *L* is the Lorenz number) from κ_{total} . The room temperature κ_{ι} + κ_{ι} is ~2.7 W m⁻¹ K⁻¹ for YbMg₂Bi_{1.96} and it is only ~0.9 W m⁻¹ K⁻¹ for Yb_{0.7}Mg_{0.3}Mg₂Bi_{1.96}, a decrease of 66% (Fig. 3(b)). Such a significant reduction in lattice thermal conductivity should be attributed to the substantial mass difference between the Yb $(173.04 \text{ g mol}^{-1})$ and Mg (24.31 g mol⁻¹) atoms. In addition, it should be noted that the bipolar thermal conductivity at elevated temperature is substantially increased with the increase of Mg concentration in the higher temperature range (Fig. 3(d)) due to the decreased band gap, which is the same mechanism as reported for various compounds, such as PbTe,^{[62](#page-7-25)} Ca_{1-x}Yb_xMg₂Bi₂,^{[44](#page-7-17)} and Mg₂Sn-Mg₂Si- $Mg_2Pb.$ ^{[63](#page-8-0)}

According to the method proposed by Kitagawa *et al*., [64](#page-8-1) the contribution of bipolar thermal conductivity *κ*B at higher temperature is roughly presented in Fig. 3(c) through separation from the total thermal conductivity *κ*_{total}. The dashed lines

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represent a linearly fitted relationship between *κ*_L and *T*⁻¹ over the temperature range from 300 to 773 K. The deviation of $κ$ _L at higher temperature indicates the obvious bipolar thermal conductivity since the bipolar effect normally does not exist in the lower temperature range. As shown in Fig. 3(c) and (d), a slight *κ*B deviation is initially observed for $Yb_{0.9}Mg_{0.1}Mg_2Bi_{1.96}$. As the Mg concentration is increased from $x = 0.1$ to $x = 0.2$ and $x = 0.3$, the *κ*^B significantly deviates from the linear relationship. This is due to the decreased band gap and therefore enhanced bipolar contribution with increasing Mg alloying concentration in Yb₁. *^x*Mg*x*Mg2Bi1.96.

The dimensionless figure of merit *ZT* of Yb_{1-x}Mg_xMg₂Bi_{1.96} is shown in Fig. 4(a). With the increasing temperature, *ZT*s increase monotonically in the lower temperature range. However, the *ZT*s of Yb_{0.7}Mg_{0.3}Mg₂Bi_{1.96} and Yb_{0.8}Mg_{0.2}Mg₂Bi_{1.96} decrease with temperature in the high temperature range due to the bipolar effect. This is in good agreement with the Seebeck coefficient and the thermal conductivity (Fig. 2(c) and Fig. 3). Benefiting from the significant decrease in thermal conductivity (especially at the lower temperature range), *ZT*s have been effectively improved for Yb1-*x*Mg*x*Mg2Bi1.96 (*x* > 0). The room-temperature *ZT* is ∼0.13 for YbMg₂Bi_{1.96} but ~0.27 for Yb_{0.7}Mg_{0.3}Mg₂Bi_{1.96}, an increase of ∼108%. At 773 K, the peak *ZT* can be ~0.8 for Yb_{0.9}Mg_{0.1}Mg₂Bi_{1.96}, due to the effectively reduced lattice thermal conductivity. In fact, the *ZT* values in the lower temperature range in our work are higher than those reported by May *et al.*[42](#page-7-21) and Shuai *et al.*[44](#page-7-17)

The average figure of merit $(ZT)_{avg}$ is calculated by the integration method over the temperature range from 300 to 773 K, as shown in Fig. 4(b). Samples alloyed with Mg show a noticeable increase in $(ZT)_{avg}$ compared to YbMg₂Bi_{1.96}. Due to the improved *ZT* in the lower temperature range, $(ZT)_{avg}$ is substantially improved from ∼0.46 for YbMg2Bi1.96 to ∼0.61 for Yb_{0.8}Mg_{0.2}Mg₂Bi_{1.96}, an enhancement of ~33%. In fact, since the engineering figure of merit (ZT)_{eng} is a better evaluation of heat-toelectricity conversion efficiency for certain materials, we also calculated (*ZT*)eng and predicted the conversion efficiency (*η*) for Yb1-*x*Mg*x*Mg2Bi1.96 based on eqns. (1)–(3): [65,](#page-8-2) [66](#page-8-3)

$$
(ZT)_{\text{eng}} = \frac{(PF)_{\text{eng}}}{\int_{\tau_c}^{\tau_h} \kappa(T) dT} (T_h - T_c)
$$
(1)

$$
(PF)_{\text{eng}} = \frac{\left(\int_{\tau_c}^{\tau_h} S(T) dT\right)^2}{\int_{\tau_c}^{\tau_h} \rho(T) d(T)}
$$
(2)

$$
\eta_{\text{max}} = \eta_c \frac{\sqrt{1 + (ZT)_{\text{eng}} (\alpha_1/\eta_c)} - 1}{\alpha_0 \sqrt{1 + (ZT)_{\text{eng}} (\alpha_1/\eta_c)} + \alpha_2},
$$
(3)

where *S*(T), *ρ*(T), and *κ*(T) are temperature-dependent thermoelectric properties, and α_i (i = 0, 1, and 2) is a dimensionless intensity factor of the Thomson effect. The hot-side temperature-dependent (ZT)_{eng} and efficiency at the cold-side temperature of 323 K are shown in Fig. 4(c) and Fig. 4(d), respectively. It is clear that both (ZT)_{eng} and efficiency increase with increasing Mg concentration from $x = 0$ to 0.2, with a slight decrease for *x* = 0.3 at high temperature. The peak (*ZT*)eng is ∼0.35

for YbMg2Bi1.96 but ∼0.55 for Yb0.8Mg0.2Mg2Bi1.96, an enhancement of ~57%. The peak efficiency is ~7.5% for YbMg2Bi_{1.96} but ~10% for Yb_{0.8}Mg_{0.2}Mg₂Bi_{1.96}, an increase of 33%.

Conclusions

In summary, solid solutions of YbMg2Bi2-Mg3Bi² were prepared and studied. Significant point defect scattering between the Yb and Mg atoms effectively reduces the lattice thermal conductivity. As a result, a relatively high peak *ZT* of ∼0.8 at 773 K can be achieved for $Yb_{0.9}Mg_{0.1}Mg_2Bi_{1.96}$. More importantly, a much higher (*ZT*)_{avg} of ~0.61 can be obtained for Yb_{0.8}Mg_{0.2}Mg₂Bi_{1.96}, which is 33% higher than that of YbMg₂Bi_{1.96}.

Author contributions

Ting Zhou, Jun Mao, Chao Wang, and Zhifeng Ren designed research; Ting Zhou performed research; Jing Jiang, Shaowei Song, Hangtian Zhu, Qing Zhu, Qinyong Zhang, Wuyang Ren, and Zhiming Wang analyzed data; and Ting Zhou, Jun Mao, Chao Wang, and Zhifeng Ren wrote the paper.

Conflicts of interest

There are no conflicts to declare.

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The thermoelectric property of $YbMg_2Bi_2-Mg_3Bi_2$ solid solution is studied.